

MS/RF PCM/PROCESS CHECKLIST SUB-WORKING GROUP MINUTES

Date: September 23, 2009

Location: Teleconference

Time: 10:00am (Pacific)

Participants:

Chelsea Boone – GSA
David Schwan – RF Micro Devices (RFMD)
Hugues Lafontaine – SiGe Semiconductor
Steffen Richter – X-FAB
Ranjeet Pancholy – Kesar Technology
Matt Engelman – Ridgetop Group
Aniruddha Joshi – Skyworks Solutions
Philippe Jansen – IMEC

Meeting Purpose:

- To gather feedback on how the Sub-Working Group should go about developing a checklist that will help in communicating basic process parameters and criteria for mixed-signal and RF processes.

End Result/Conclusions:

- There was some confusion about the purpose of the PCM checklist. The following points were discussed:
 - It is a standard list of parameters that you would measure for a device
 - It will help measure the health of the line
 - Provides a standard definition and measurement technique for process parameters
 - Customers can understand what the yield implication is for their parts, not just quality
 - It is for monitoring, not characterization
 - Foundry does not have to support all on the list
 - Will not only cover CMOS
 - Will standardize how information is collected
 - Will provide the foundry with some guidance, and less customer training will be required
- Per the working group's feedback, changes were made to the PCM parameter list. To view the changes made, please see Version 2 of the PCM parameter list.
- Next Meeting: Now that we have identified the parameters, we need to identify which methodology is used. Foundries have different ways of saying what the result is. We want to make sure the values of the parameters are meaningful to the fabless customer. Measurements methodology and terminology standardization meeting - **October 21, 2009, 10:00am (Pacific)**